

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|---|--|------------------|---------|------------------|
| L1 | 1 | 702/132.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated adj circuit or wafer) same (power or current) same (ambient near3 temperature) same body same voltage same bias\$3 same (junction near3 temperature)) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:05 |
| L2 | 0 | 324/755.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated adj circuit or wafer) same (power or current) same (ambient near3 temperature) same body same voltage same bias\$3 same (junction near3 temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/25 13:06 |
| L3 | 0 | 365/201.ccls.and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated adj circuit or wafer) same (power or current) same (ambient near3 temperature) same body same voltage same bias\$3 same (junction near3 temperature)) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:07 |
| L4 | 0 | 324/760.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated adj circuit or wafer) same (power or current) same (ambient near3 temperature) same body same voltage same bias\$3 same (junction near3 temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/25 13:01 |
| L5 | 0 | 324/754.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated adj circuit or wafer) same (power or current) same (ambient near3 temperature) same body same voltage same bias\$3 same (junction near3 temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:07 |
| L6 | 0 | 324/765.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated adj circuit or wafer) same (power or current) same (ambient near3 temperature) same body same voltage same bias\$3 same (junction near3 temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:07 |
| L7 | 0 | 438/15.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated adj circuit or wafer) same (power or current) same (ambient near3 temperature) same body same voltage same bias\$3 same (junction near3 temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:07 |

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| L8 | 0 | 714/724.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated adj circuit or wafer) same (power or current) same (ambient near3 temperature) same body same voltage same bias\$3 same (junction near3 temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:08 |
| L9 | 0 | 324/755.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated with circuit or wafer) same (power or current) same (ambient same temperature) same body same voltage same bias\$3 same (junction same temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/25 13:05 |
| L10 | 1 | 702/132.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated) same (circuit or wafer) same (power or current) same (ambient same temperature) same body same voltage same bias\$3 same (junction same temperature)) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:06 |
| L11 | 0 | 324/755.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated) same (circuit or wafer) same (power or current) same (ambient same temperature) same body same voltage same bias\$3 same (junction same temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/25 13:06 |
| L13 | 0 | 365/201.ccls.and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated) same (circuit or wafer) same (power or current) same (ambient same temperature) same body same voltage same bias\$3 same (junction same temperature)) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:07 |
| L14 | 0 | 324/754.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated) same (circuit or wafer) same (power or current) same (ambient same temperature) same body same voltage same bias\$3 same (junction same temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:07 |
| L15 | 0 | 324/765.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated) same (circuit or wafer) same (power or current) same (ambient same temperature) same body same voltage same bias\$3 same (junction same temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:07 |
| L16 | 0 | 438/15.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated) same (circuit or wafer) same (power or current) same (ambient same temperature) same body same voltage same bias\$3 same (junction same temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:07 |

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| L17 | 0 | 714/724.ccls. and ((determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated) same (circuit or wafer) same (power or current) same (ambient same temperature) same body same voltage same bias\$3 same (junction same temperature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:08 |
| S1 | 176 | 702/132.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 12:58 |
| S2 | 75 | 702/131.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:45 |
| S3 | 633 | 702/130.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:45 |
| S4 | 433 | 702/64.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:46 |
| S5 | 116993 | temperature and (integrat\$2 or IC) and test | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 10:54 |
| S6 | 24 | S1 and S5 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:51 |
| S7 | 5 | S2 and S5 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:50 |
| S8 | 93 | S3 and S5 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:50 |
| S9 | 49 | S4 and S5 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:50 |

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|-----|------|--|--|----|-----|------------------|
| S10 | 4023 | temperature same (integrat\$2 or IC) same test | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:50 |
| S11 | 8 | S1 and S10 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:52 |
| S12 | 0 | S2 and S10 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:52 |
| S13 | 18 | S3 and S10 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:51 |
| S14 | 4 | S4 and S10 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:51 |
| S15 | 166 | S10 and "702"/\$.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:58 |
| S16 | 2 | "20040183588" | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:00 |
| S17 | 1 | "20050088137" | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 11:59 |
| S18 | 431 | 327/545.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:00 |
| S19 | 0 | S18 and S10 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:01 |
| S20 | 402 | 318/806.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:01 |

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|-----|-------|--|--|----|-----|------------------|
| S21 | 8 | S18 and S5 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:01 |
| S22 | 12 | S20 and S5 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:08 |
| S23 | 21091 | ((voltage or power or current) with control\$4) and (((semiconductor with substrate) or (integrated adj circuit\$1) or wafer\$1 or chip\$1) with temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:46 |
| S24 | 4104 | S23 and ((environmental or ambient) near5 temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:47 |
| S25 | 688 | S24 and (voltage near3 bias\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:17 |
| S26 | 78 | S25 and (thermal near4 resistance) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:16 |
| S27 | 495 | S25 and ((power or voltage) near4 supply) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:19 |
| S28 | 241 | S25 and ((power or voltage) near4 supply with temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:20 |
| S29 | 228 | S28 and (current with voltage) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 12:20 |
| S30 | 37 | 702/129.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:44 |
| S31 | 1 | S30 and (temperature and (integrat\$2 or IC) and test) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:46 |

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|-----|-------|---|--|----|-----|------------------|
| S32 | 4207 | 324/765.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:46 |
| S33 | 821 | S32 and (temperature and (integrat\$2 or IC) and test) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:46 |
| S34 | 192 | S32 and (((voltage or power or current) with control\$4) and (((semiconductor with substrate) or (integrated adj circuit\$1) or wafer\$1 or chip\$1) with temperature)) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:46 |
| S35 | 36 | S34 and ((environmental or ambient) near5 temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:47 |
| S36 | 21091 | ((voltage or power or current) with control\$4) and (((semiconductor with substrate) or (integrated adj circuit\$1) or wafer\$1 or chip\$1) with temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:48 |
| S37 | 4104 | S36 and ((environmental or ambient) near5 temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:48 |
| S38 | 688 | S37 and (voltage near3 bias\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/11/10 15:32 |
| S39 | 241 | S38 and ((power or voltage) near4 supply with temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:48 |
| S40 | 228 | S39 and (current with voltage) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/05/24 13:48 |
| S41 | 39 | S40 and (junction near5 temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/05/16 14:51 |
| S42 | 14662 | (junction near5 temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/11/10 15:31 |

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| S43 | 1864 | body near5 voltage near5 bias\$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/11/10 15:36 |
| S44 | 18 | S42 and S43 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/11/10 15:32 |
| S45 | 75 | body near5 voltage near5 bias\$3 with temperature | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/11/10 16:06 |
| S46 | 78 | body near5 voltage near5 bias\$3 with temperature | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/11/10 15:36 |
| S47 | 83 | body near5 voltage near5 bias\$3 with (temperature or thermal) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/11/10 15:37 |
| S48 | 136 | body near5 voltage near5 bias\$3 same (temperature or thermal) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/11/10 16:07 |
| S49 | 38 | body near5 voltage near5 bias\$3 same (regulat\$3 or desired or optimaliz\$3 or stabliz\$3 or control\$4 or maintain\$3 or management or optimum) near5 (temperature or thermal) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/24 09:34 |
| S50 | 6 | S49 and junction with temperature | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/11/10 16:04 |
| S51 | 2 | "6100751".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/11/11 09:52 |
| S53 | 2020 | (measur\$5 or determin\$3 or obtain\$3 or calculat\$3 or estimat\$3 or monitor\$3) with (power near4 consum\$5) with (die or chip or IC or integrated adj circuit or wafer) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/16 11:46 |
| S55 | 13613 | (measur\$5 or determin\$3 or obtain\$3 or calculat\$3 or estimat\$3 or monitor\$3) near4 temperature with (die or chip or IC or integrated adj circuit or wafer) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/16 11:47 |

EAST Search History

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|-----|-------|---|--|----|-----|------------------|
| S56 | 113 | S53 and S55 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/16 13:40 |
| S57 | 2020 | (measur\$5 or determin\$3 or obtain\$3 or calculat\$3 or estimat\$3 or monitor\$3) with (power near4 consum\$5) with (die or chip or IC or integrated adj circuit or wafer) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/16 13:40 |
| S58 | 13613 | (measur\$5 or determin\$3 or obtain\$3 or calculat\$3 or estimat\$3 or monitor\$3) near4 temperature with (die or chip or IC or integrated adj circuit or wafer) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/17 09:21 |
| S59 | 113 | S57 and S58 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/16 13:41 |
| S60 | 58 | S59 and voltage with temperature | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/16 13:41 |
| S61 | 524 | (power near4 consum\$5) and (ambient near3 temperature) and (junction near5 temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/05/16 14:52 |
| S62 | 596 | (power near4 consum\$5) and (ambient near3 temperature) and (junction near5 temperature) and (IC or integrated adj circuit or die or wafer or chip or substrate or CPU or processor or device or UUT or DUT) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/16 14:54 |
| S63 | 25 | (power near4 consum\$5) same (ambient near3 temperature) same (junction near5 temperature) same (IC or integrated adj circuit or die or wafer or chip or substrate or CPU or processor or device or UUT or DUT) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/16 15:04 |
| S64 | 18 | S63 and voltage | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/16 15:04 |
| S65 | 74 | (determin\$3 or calculat\$3 or estimat\$3 or comput\$3) near4 junction adj temperature same (die or chip or IC or integrated adj circuit or wafer) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/25 10:58 |

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| S66 | 20 | S65 and (power or current) same (ambient near3 temperature) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/05/17 09:23 |
| S67 | 9 | body near5 voltage near5 bias\$3 same (junction near3 temperature) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/25 11:07 |
| S68 | 2 | ("6100751").PN. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/24 09:47 |
| S69 | 6 | body near5 voltage near5 bias\$3 same (junction adj temperature) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/24 10:12 |
| S70 | 94 | ("6002620" "4997366" "5313085" "5349559" "5426616" "5512353" "5523619" "5770504" "5798281" "5817543" "5847591" "5867421" "6014052" "6091287" "6141245" "6243283" "6288561" "6323663" "6838896" "6891387" "20030151421" "20040222809" "5408951" "5694048" "5938427" "6109767" "6175241" "5532612" "4495622" "4514786" "4992849" "4992850" "5196785" "5234149" "5440240" "5530376" "5572140" "5585282" "5705933" "5781022" "5789794" "5808947" "5861660" "5883008" "5954832" RE36325 "6221682" "6221682" "4281449" "4288911").pn. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/25 10:50 |
| S71 | 785 | 324/760.ccls. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/25 13:01 |
| S72 | 943 | 324/755.ccls. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/25 13:00 |
| S73 | 4917 | 324/765.ccls. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:01 |

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| S74 | 4523 | 324/754.ccls. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:01 |
| S75 | 3416 | 714/724.ccls. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:02 |
| S76 | 858 | 438/15.ccls. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:02 |
| S77 | 3488 | 365/201.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/10/25 13:01 |
| S78 | 1 | (determin\$3 or calculat\$3 or estimat\$3 or comput\$3) same temperature same (die or chip or IC or integrated adj circuit or wafer) same (power or current) same (ambient near3 temperature) same body same voltage same bias\$3 same (junction near3 temperature).clm. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2006/10/25 12:58 |
| S79 | 1 | (body near5 voltage near5 bias\$3 same (junction near3 temperature)).clm. | US-PGPUB | OR | ON | 2006/10/25 11:08 |
| S80 | 1 | (integrated adj circuit same voltage with bias\$3 same (junction near3 temperature)).clm. | US-PGPUB | OR | ON | 2006/10/25 11:09 |